## Issue Classification

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/Dalena Tran/

(Primary Examiner)

**ORIGINAL** 

Application/Control No.	Applicant(s)/Patent Under Reexamination
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10809399	YAMAKAWA ET AL.
Examiner	Art Unit
Dalena Tran	3664
Baioria Trair	0001

INTERNATIONAL CLASSIFICATION

CLASS SI			SUBCLASS		CLAIMED						NON-CLAIMED				
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CROSS REFERENCE(S)			S)												
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NONE (Assistant Examiner) (Date)											10	ıaı C	iaiiiis	o Alloweu:	
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O.G. Print Claim(s)

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O.G. Print Figure

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